



CHAPTER 3: CRYSTAL STRUCTURES X-Ray Diffraction (XRD)

ISSUES TO ADDRESS...

- Historical retrospective
- Henry Bragg Equation
- XRD-analysis
- How to read XRD patterns?
- Exclusions
- What questions can be answered by XRD method?





Scale of Structure Organization



Crystal Structure



(b) interstitial impurity

(d) anion vacancy

(f) substitution of anion

(h) A_B antisite defect

(g) BA antisite defect

Practical questions to address:

How to define what crystal structure do we have? Or in another words: what phases do we have? Do we have defects or strain in our structure?

From art to science

Materials science became a real science due to the development of modern analysis and imaging techniques.

Modern analysis and imaging techniques become possible due to developments in the materials science

Nature of light

- Newton: particles (*corpuscles*)
- Huygens: waves
- **Thomas Young** double slit experiment (1801)
- Path difference \Rightarrow phase difference
- Light consists of waves !
- Wave-particle duality



Schematic diagram of Young's double slit experiment. Slits S_1 and S_2 behave as coherent source of light waves that produce *interference pattern* on the viewing screen

See additional file Interference of Light Waves on my website

Wilhelm Conrad Röntgen Discovered the 'Röntgen' rays in 1895.Named these 'X=rays'.

Jnvisible rays

X-radiation (composed of **X-rays**) is a form of electromagnetic radiation. Most X-rays have a wavelength in the range of 0.01 to 10 nm, corresponding to frequencies in the range 30 petahertz to 30 exahertz (3×10^{16} Hz to 3×10^{19} Hz) and energies in the range 100 eV to 100 kEV.





Radiation went straight through a closed, black carton, hitting a fluorescent screen.

Nobel prize 1901





- The periodicity and interatomic spacing of crystals had been deduced earlier (e.g. Auguste Bravais).
- von Laue realized that if X-rays were waves with short wavelength, interference phenomena should be observed like in Young's double slit experiment.
- Experiment in 1912, Nobel Prize in 1914

Max von Lane



Sir William Henry Bragg:

•William Henry and William Lawrence Bragg (father and son) found a simple interpretation of von Laue's experiment.

• They assume that each crystal plane reflects radiation as a mirror and analyze this situation for

cases of constructive and destructive interference.







Conditions for reflection:

The most important thing in science is not so much to obtain new facts as to discover new ways of thinking about them.

Bragg's law



Path difference $\Delta = 2x => phase shift$ Constructive interference if $\Delta = n\lambda$ This gives the criterion for constructive interference:

$$\Rightarrow \Delta = 2d_{hkl}\sin(\theta) = n\lambda$$

Bragg's law tells you at which angle θ_B to expect maximum diffracted intensity for a particular family of crystal planes. For large crystals, all other angles give zero intensity.

Conclusions:

DIFFRACTION AND THE BRAGG EQUATION

Max von Laue was the first to suggest that crystals might diffract X-rays and he also provided the first explanation for the diffraction observed. However, it is the explanation provided by Bragg that is simpler and more popular.

In the **Bragg** view crystal planes act a mirrors. Constructive interference is observed when the path difference between the two reflected beams in (a) = $n\lambda$. The path difference in (a) is 2my. Since my/d = $sin\theta$ 2my = $2dsin\theta = n\lambda$ where d is the interplanar spacing.



 $2d_{(1,0,0)}\sin\theta = 2\lambda$ This is a second order reflection

Typical View of X-ray Diffractometer







The powder diffractometers typically use the Bragg-Brentano geometry



- The incident angle, ω , is defined between the X-ray source and the sample.
- The diffracted angle, 2θ , is defined between the incident beam and the detector angle.
- The incident angle ω is always $\frac{1}{2}$ of the detector angle 2θ .
- In a θ :2 θ instrument (e.g. Rigaku RU300), the tube is fixed, the sample rotates at θ °/min and the detector rotates at 2 θ °/min.
- In a θ : θ instrument (e.g. PANalytical X'Pert Pro), the sample is fixed and the tube rotates at a rate $-\theta$ °/min and the detector rotates at a rate of θ °/min.

Production of X-rays

*X-rays are produced by bombarding a metal target (Cu, Mo usually) with a beam of electrons emitted from a hot filament (often tungsten). The incident beam will ionize electrons from the K-shell (1s) of the target atom and X-rays are emitted as the resultant vacancies are filled by electrons dropping down from the L (2P) or M (3p) levels. This gives rise to K_a and K_b lines.



Cu $K_{\alpha} = 1.5418 \text{ Å}$ Mo $K_{\alpha} = 0.7107 \text{ Å}$

Basic Features of Typical XRD Experiment



A single crystal specimen in a Bragg-Brentano diffractometer would produce only one family of peaks in the diffraction pattern.



At 20.6 °2 θ , Bragg's law fulfilled for the (100) planes, producing a diffraction peak.

The (110) planes would diffract at 29.3 °20; however, they are not properly aligned to produce a diffraction peak (the perpendicular to those planes does not bisect the incident and diffracted beams). Only background is observed. The (200) planes are parallel to the (100) planes. Therefore, they also diffract for this crystal. Since d_{200} is $\frac{1}{2} d_{100}$, they appear at 42 °20.

A polycrystalline sample should contain thousands of crystallites. Therefore, all possible diffraction peaks should be observed.



- For every set of planes, there will be a small percentage of crystallites that are properly oriented to diffract (the plane perpendicular bisects the incident and diffracted beams).
- Basic assumptions of powder diffraction are that for every set of planes there is an equal number of crystallites that will diffract and that there is a statistically relevant number of crystallites, not just one or two.

Example: Diffraction Patterns

- Each peak represents the solution to Bragg's law for known radiation wavelength ($\lambda = 0.154$ nm)
- The unique relationship between such patterns and crystal structures provide a powerful tool for identification of the phase composition of powders and polycrystalline materials.



Diffraction pattern



d-spacing in different crystal systems



Powder Preparation

★It needs to be a powder

★It needs to be a pure powder

- Its nice to have about 1/2 g of sample, but one can work with less
- The powder needs to be packed tightly in the sample holder. Lose powders will give poor intensities.

Data Collection

*The scattering intensity drops as 1/2(1+cos²2θ)
*This means that you don't get much intensity past 70 ° 2θ. A good range is 10-70 ° 2θ.
*How long should you collect (time per step)?
*Depends on what you want to do!
*Routine analysis may only take 30-60 min.
*Data for Rietveld analysis may take 12-18 hours to collect

Indexing Patterns

Indexing is the process of determining the unit cell dimensions from the peak positions

- *Manual indexing (time consuming...but still useful)
- *Pattern matching/auto indexing (JADE or other computer based indexing software)

Cubic pattern



Relationship between diffraction peaks, miller indices and lattice spacings

Simple cubic material $\mathbf{a} = 5.0 \text{ Å}$

hkl	d(Å)	2Θ
100	5.00	17.72
110	3.54	25.15
111	2.89	30.94



Bragg Equation: $n\lambda = 2dsin\theta$

How many lattice planes are possible? How many d-spacings? The number is large but finite. $n\lambda = 2d\sin\theta$ so if theta = 180, then d = $\lambda/2$. For Cu radiation that means that we can only see d-spacings down to 0.77 Å for Mo radiation, down to about 0.35 Å



1.file number 2.three strongest lines 3.lowest-angle line 4.chemical formula and name 5.data on diffraction method used 6.crystallographic data 7.optical and other data 8.data on specimen 9.data on diffraction pattern.

Joint Committee on Powder Diffraction Standards, JCPDS (1969) Replaced by International Centre for Diffraction Data, ICDF (1978)

Structure Factor

The general expression for :

$$F \equiv \sum_{n=1}^{N} f_n e^{2\pi i (hu_n + kv_n + lw_n)}$$

Now we apply this to various crystals. First, consider examples of crystals with a basis group of just <u>one</u> <u>atom per lattice point</u>, with atomic scattering factor *f*. The results are valid *for any crystal system*.

Primitive Cells

This is really simple! N = 1, so

$$F \equiv \sum_{n=1}^{N} f_n e^{2\pi i (hu_n + kv_n + hw_n)} = f e^{2\pi i (hu + kv + hw)}$$

<u>Define</u> the position of the cell so that our atom is at uvw = 000; then (hu+kv+lw) = 0, and we get just

$$F = f e^{2\pi i(0)} = f$$

$$F = f$$

SO

Basis and Bravais Structure Factor Terms

$$F = \sum_{n=1}^{N_p} e^{2\pi i \mathbf{g} \cdot \mathbf{r}_n} \sum_{m=1}^{N_b} f_m e^{2\pi i \mathbf{g} \cdot \mathbf{r}_m} = F_{BR} F_{BA}$$

The following simple table giving the integer values of F_{BR} for the different types of centering translations. Keep in mind that these are <u>valid for any crystal system</u>.

Centering type	M issing Reflections $(F_{BR} = 0)$	Possible Reflections (FBR ° 0)	Bravais Term FBR for possible reflections
P (primitive)	None	All	1
I (body-centered)	(h + k + l) odd	(h + k + l) even	2
A (base-centered on A face)	(k + l) odd	(k + l) even	2
B (base-centered on B face)	(h + l) odd	(h + l) even	2
C (base-centered on C face)	(h + k) odd	(h + k) even	2
F (face-centered)	hkl mixed	hkl unmixed	4

What Information Do We Get or Can We Get From Powder X-ray Diffraction

Lattice parameters
Phase identity
Phase purity

*Crystallinity

★Crystal structure

★Percent phase composition

What Information Do We NOT Get From Powder X-ray Diffraction

★Elemental analysis -

*How much lithium is in this sample?

*****Is there iron in this sample

*What elements are in this sample

★Tell me what this sample is ????

*Unless you know something about this sample, powder XRD won't have answers !!!

Summary

X-rays are electromagnetic radiation of wavelength about $1 \text{ Å} (10^{-10} \text{ m})$, which is about the same size as an atom.

The discovery of X-rays in 1895 enabled scientists to probe crystalline structure at the atomic level. X-ray diffraction has been in use in two main areas, for the fingerprint characterization of crystalline materials and the determination of their structure. Each crystalline solid has its unique characteristic X-ray powder pattern which may be used as a "fingerprint" for its identification. Once the material has been identified, X-ray crystallography may be used to determine its structure, i.e. how the atoms pack together in the crystalline state and what the interatomic distance and angle are etc. X-ray diffraction is one of the most important characterization tools used in solid state chemistry and materials science.

We can determine the size and the shape of the unit cell for any compound most easily using X-ray diffraction.